

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination OHMURA ET AL.	
		Examiner	Art Unit	Page 1 of 1
		Christopher D RoDee	1756	

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-2001/0031412	10-2001	Itami et al.	430/110.3
	C	US-2002/0037469	03-2002	Kohyama et al.	430/110.3
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	N	JP 2001255685 A	09-2001	Japan	ITAMI et al.	G03G 05/147
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**NON-PATENT DOCUMENTS**

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